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Application/Control No.	Applicant(s)/ Reexamination
40/747 040	10111441154

10/717,913 Examiner

David E. Bochna

Applicant(s)/Patent under Reexamination
ICHIMURA ET AL.
Art Unit

3679

SEARCHED				
Class	Subclass	Date	Examiner	
285	3,82	9/10/2007	DB	
	202			
	203			
29	509			
	511			
	520			
	523			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
288	382	9/10/2007	DB	
	203			

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